

IN THE CLAIMS:

Amend claims 1, 3, 10, 12 and 13 and cancel claim 2 without prejudice or admission as shown in the following listing of claims, which replaces all previous listings and versions of claims.

1. (currently amended) An electrical property evaluation apparatus for measuring an electrical property of an object, comprising:

a magnetic field generating mechanism that generates a magnetic field in a target area on an object to be measured, the magnetic field generating mechanism including a pair of magnetic field coils, each magnetic field coil having a magnetic pole member, and the magnetic field coils being located opposite to each other;

a magnetic sensor for measuring the magnetic field near the target area;

a cantilever having a conducting probe, the cantilever being supported so that the probe can be brought into contact with the target area, and the cantilever and the magnetic sensor being located in a center location between the pair of magnetic pole members;

a moving mechanism that moves the cantilever relative to the object to carry out scanning while keeping the probe in contact with the object;

a bending measurement mechanism that measures an amount of bending of the cantilever when the probe is brought into contact with the object;

a control section that controls the moving mechanism so as to maintain the bending amount of the cantilever constant;

a voltage source for applying a voltage to the probe; and

an electrical property measuring section that measures a current or an electrical resistance between the probe and the object in contact with each other.

2. (canceled)

3. (currently amended) An electrical property evaluation apparatus according to ~~claim 2~~ claim 1; wherein the pair of magnetic pole members are shaped into a rod or strip form and disposed at an inclination to a surface of the target area with tips thereof facing toward the target area.

4.-9. (canceled)

10. (currently amended) An electrical property evaluation apparatus for measuring an electrical property of an object, comprising:

a magnetic field generating mechanism that generates a magnetic field in a target area of an object to be measured, the magnetic field generating mechanism including a pair of spaced-apart magnetic field coils each having a magnetic pole member;

a magnetic sensor for measuring the magnetic field near the target area;

a ~~contact~~ cantilever having a conducting probe and being supported so that the probe can be brought into contact with the target area, the ~~contact~~ cantilever and the magnetic sensor being located in a center region between the pair of magnetic pole members;

a voltage source for applying a voltage to the probe; and

an electrical property measuring section that measures a current or an electrical resistance between the probe and the object in contact with each other.

11. (previously presented) An electrical property evaluation apparatus according to claim 10; wherein the pair of magnetic pole members have an elongate shape and are disposed at an inclination relative to a surface of the target area such that tips of the magnetic pole members face toward the target area.

12. (currently amended) An electrical property evaluation apparatus according to claim 11; wherein the ~~eontact~~ cantilever is bendable; and further including a moving mechanism that scans the ~~eontact~~ cantilever relative to the object while keeping the probe in contact with the object; a bending measurement mechanism that measures an amount of bending of the ~~eontact~~ cantilever when the probe is brought into contact with the object; and a control section that controls the moving mechanism so as to maintain the bending amount of the ~~eontact~~ cantilever constant.

13. (currently amended) An electrical property evaluation apparatus according to claim 10; wherein the ~~eontact~~ cantilever is bendable; and further including a moving mechanism that scans the ~~eontact~~ cantilever relative to the object while keeping the probe in contact with the object; a bending measurement mechanism that measures an amount of bending of the ~~eontact~~ cantilever when the probe is brought

into contact with the object; and a control section that controls the moving mechanism so as to maintain the bending amount of the ~~contact~~ cantilever constant.